

Application/Control	No. Applicant(s)/Patent und Reexamination	er
09/066,255	BUECHLER ET AL.	
Examiner	Art Unit	
Mark I Shibuya	1630	

	SEAD	CHED	
	SEAR	CHED	
Class	Subclass	Date	Examiner
435	5,6,7.1	411105	mg
436	96	4/1/05	ny
540	121	4/1/05	mz

ראו	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
435	5, 6, 7.1	4/1/2005	MS		
436	96	4/1/2005	MS		
540	121	4/1/2005	MS		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST, interference search	4/1/2005	MS		